TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π-MOSIV)

2SK3798

Switching Regulator Applications

• Low drain-source ON resistance: RDS (ON) = 2.5Ω (typ.)

• High forward transfer admittance: $|Y_{fs}| = 2.8 \text{ S (typ.)}$

• Low leakage current: IDSS = 100 μ A (VDS = 720 V)

• Enhancement-mode: $V_{th} = 2.0 \sim 4.0 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA})$

Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Drain-source voltage		V_{DSS}	900	V	
Drain-gate voltage ($R_{GS} = 20 \text{ k}\Omega$)		V_{DGR}	900	V	
Gate-source voltage		V _{GSS}	±30	V	
	DC (Note 1)	ID	4	А	
Drain current	Pulse (t = 1 ms) (Note 1)	I _{DP}	12		
Drain power dissipation (Tc = 25°C)		P _D	40	W	
Single pulse avalanche energy (Note 2)		E _{AS}	345	mJ	
Avalanche current		I _{AR}	4	Α	
Repetitive avalanche energy (Note 3)		E _{AR}	4.0	mJ	
Channel temperature		T _{ch}	150	°C	
Storage temperature range		T _{stg}	-55~150	°C	

Unit: mm \$\int_{0.69 \to 0.15}^{0.69 \to 0.15} \frac{1}{2.54} \frac{2}{2.54} \fr

Weight: 1.7 g (typ.)

Thermal Characteristics

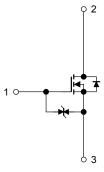
Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	3.125	°C/W
Thermal resistance, channel to ambient	R _{th (ch-a)}	62.5	°C/W

Note 1: Please use devices on conditions that the channel temperature is below 150°C.

Note 2: V_{DD} = 90 V, T_{ch} = 25°C, L = 39.6 mH, I_{AR} = 4.0 A, R_G = 25 Ω

Note 3: Repetitive rating: Pulse width limited by maximum channel temperature

This transistor is an electrostatic sensitive device. Please handle with caution.





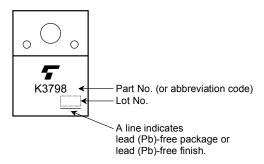
Electrical Characteristics (Ta = 25°C)

Chara	acteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I _{GSS}	$V_{GS} = \pm 30 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μΑ
Gate-source brea	akdown voltage	V (BR) GSS	$I_G = \pm 10 \mu A$, $V_{DS} = 0 V$	±30	_	_	V
Drain cut-off curr	ent	I _{DSS}	V _{DS} = 720 V, V _{GS} = 0 V		_	100	μΑ
Drain-source bre	akdown voltage	V (BR) DSS	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	900	_	_	V
Gate threshold vo	oltage	V _{th}	V _{DS} = 10 V, I _D = 1 mA	2.0	_	4.0	V
Drain-source ON	resistance	R _{DS (ON)}	V _{GS} = 10 V, I _D = 2 A		2.5	3.5	Ω
Forward transfer	admittance	Y _{fs}	V _{DS} = 20 V, I _D = 2 A	1.4	2.8	_	S
Input capacitance	e C _{iss}		_	800	_		
Reverse transfer capacitance		C _{rss}	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	_	20	_	pF
Output capacitance		Coss			85	_	
Switching time	Rise time	t _r	V_{GS} $V_{OD} \simeq 200 \text{ V}$ $V_{DD} \simeq 200 \text{ V}$	_	20	_	
	Turn-on time	t _{on}		_	65	_	
	Fall time	t _f		_	45	_	ns
	Turn-off time	t _{off}	Duty ≦ 1%, t _W = 10 μs	_	165	_	
Total gate charge		Qg		_	26	_	
Gate-source charge		Q _{gs}	$V_{DD} \simeq 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 4 \text{ A}$	_	14	_	nC
Gate-drain charge		Q _{gd}		_	12		

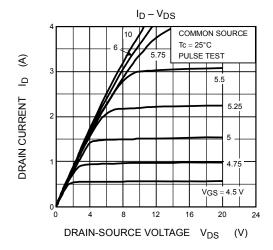
Source-Drain Ratings and Characteristics (Ta = 25°C)

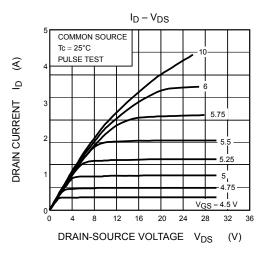
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	_	_	_	4	Α
Pulse drain reverse current (Note 1)	I _{DRP}	_	_	_	12	Α
Forward voltage (diode)	V _{DSF}	I _{DR} = 4 A, V _{GS} = 0 V	_	_	-1.7	V
Reverse recovery time	t _{rr}	$I_{DR} = 4 \text{ A}, V_{GS} = 0 \text{ V},$	_	1100	_	ns
Reverse recovery charge	Q _{rr}	dI _{DR} /dt = 100 A/μs	_	8.3	_	μС

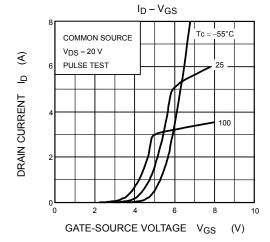
Marking

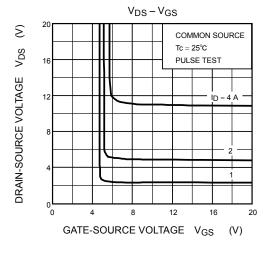


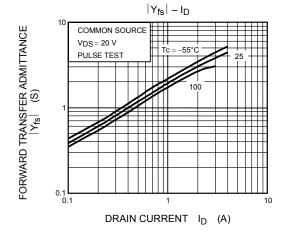
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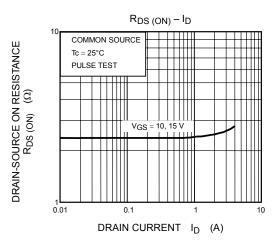


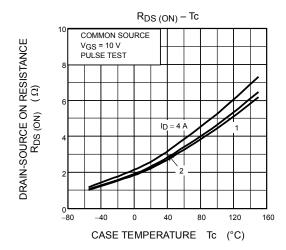


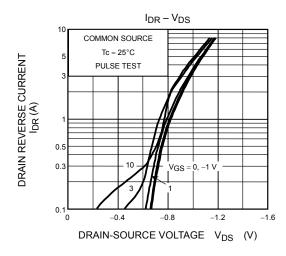


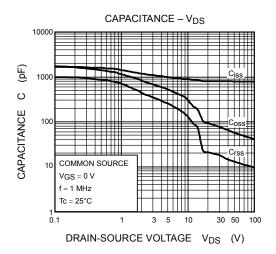


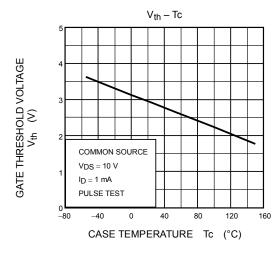


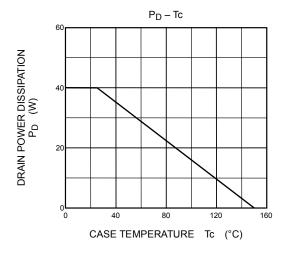


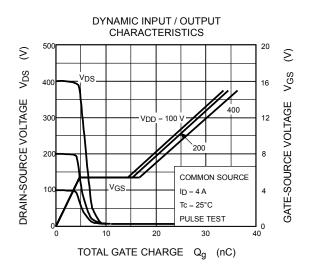


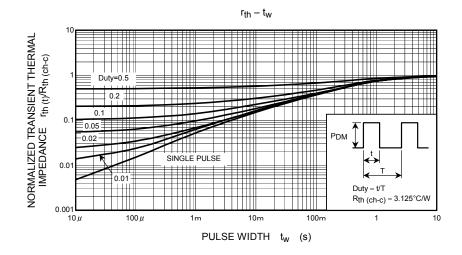


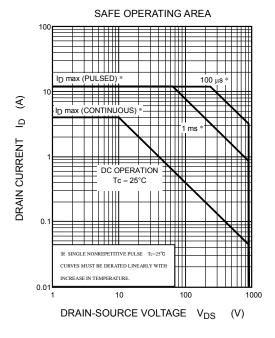


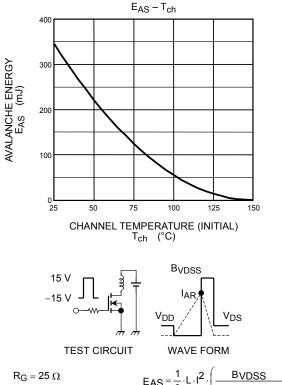












$$R_G = 25 \Omega$$

 $V_{DD} = 90 \text{ V}, L = 39.6 \text{mH}$ $E_{AS} = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{BVDSS}{BVDSS} - V_{DD} \right)$

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